



## General description

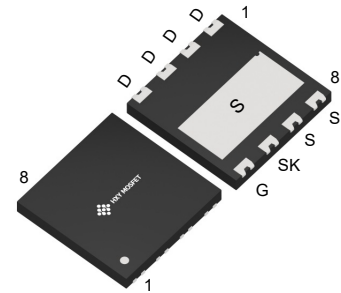
650V GaN-on-Silicon Enhancement-mode  
Power Transistor in Dual Flat No-lead Package  
(DFN) with 8 mm × 8 mm size .

## Features

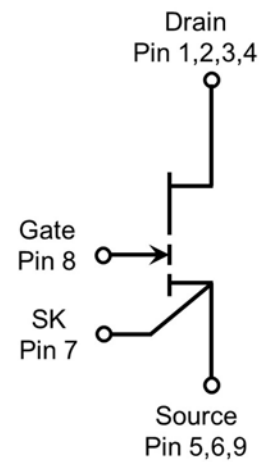
- Enhancement-mode transistor - normally-OFF power switch
- Ultra-high switching frequency
- No reverse-recovery charge
- Low gate charge, low output charge
- Qualified for industrial applications according to JEDEC Standards
- ESD safeguard
- RoHS, Pb-free, REACH-compliant

## Applications

- AC-DC converters
- DC-DC converters
- Totem pole PFC
- Fast battery charging
- High-density power conversion
- High-efficiency power conversion



DFN8X8



Gate	8
Drain	1, 2, 3, 4
Kelvin Source	7
Source	5, 6, 9



## Maximum Ratings

at  $T_j = 25\text{ }^{\circ}\text{C}$  unless otherwise specified. Continuous application of maximum ratings can deteriorate transistor lifetime.  
For further information, contact CloudSemi sales office.

**Table 3 Maximum Rating**

Parameters	Symbols	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Drain-source voltage	$V_{DS, \max}$	-	-	650	V	$V_{GS} = 0\text{ V}$ , $I_D = 10\text{ }\mu\text{A}$
Drain-source voltage transient <sup>1</sup>	$V_{DS, \text{transient}}$	-	-	750	V	$V_{GS} = 0\text{ V}$ , $V_{DS} = 750\text{ V}$
Continuous current, drain-source	$I_D$	-	-	17	A	$T_c = 25\text{ }^{\circ}\text{C}$
Pulsed current, drain-source <sup>2</sup>	$I_{D, \text{pulse}}$	-	-	32	A	$T_c = 25\text{ }^{\circ}\text{C}$ ; $V_G = 6\text{ V}$
Pulsed current, drain-source <sup>2</sup>	$I_{D, \text{pulse}}$	-	-	18	A	$T_c = 125\text{ }^{\circ}\text{C}$ ; $V_G = 6\text{ V}$
Gate-source voltage, continuous <sup>3</sup>	$V_{GS}$	-1.4	-	+7	V	$T_j = -55\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$
Gate-source voltage, pulsed	$V_{GS, \text{pulse}}$	-	-	+10	V	$T_j = -55\text{ }^{\circ}\text{C}$ to $150\text{ }^{\circ}\text{C}$ ; $t_{\text{Pulse}} = 50\text{ ns}$ , $f = 100\text{ kHz}$ ; open drain
Power dissipation	$P_{\text{tot}}$	-	-	113	W	$T_c = 25\text{ }^{\circ}\text{C}$
Operating temperature	$T_j$	-55	-	+150	$^{\circ}\text{C}$	
Storage temperature	$T_{\text{stg}}$	-55	-	+150	$^{\circ}\text{C}$	

1.  $V_{DS, \text{transient}}$  is intended for surge rating during non-repetitive events,  $t_{\text{Pulse}} < 1\text{ }\mu\text{s}$ .

2. Pulse width =  $10\text{ }\mu\text{s}$ .

3. The minimum  $V_{GS}$  is clamped by ESD protection circuit, as shown in Figure 8.

## Thermal Characteristics

**Table 4 Thermal Characteristics**

Parameters	Symbols	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Thermal resistance, junction-case	$R_{\text{thJC}}$	-	-	1.1	$^{\circ}\text{C/W}$	
Reflow soldering temperature	$T_{\text{sold}}$	-	-	260	$^{\circ}\text{C}$	MSL3



## Electrical Characteristics

at  $T_j = 25\text{ }^{\circ}\text{C}$ , unless specified otherwise.

**Table 5 Static Characteristics**

Parameters	Symbols	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Gate threshold voltage	$V_{GS(TH)}$	1.2	1.7	2.5	V	$I_D = 17.2\text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 25\text{ }^{\circ}\text{C}$
		-	1.6	-		$I_D = 17.2\text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 125\text{ }^{\circ}\text{C}$
Drain-source leakage current	$I_{DSS}$	-	0.6	20	$\mu\text{A}$	$V_{DS} = 650\text{ V}$ ; $V_{GS} = 0\text{ V}$ ; $T_j = 25\text{ }^{\circ}\text{C}$
		-	1	-		$V_{DS} = 650\text{ V}$ ; $V_{GS} = 0\text{ V}$ ; $T_j = 125\text{ }^{\circ}\text{C}$
Gate-source leakage current	$I_{GSS}$	-	40	200	$\mu\text{A}$	$V_{GS} = 6\text{ V}$ ; $V_{DS} = 0\text{ V}$
Drain-source on-state resistance	$R_{DS(on)}$	-	100	140	$\text{m}\Omega$	$V_{GS} = 6\text{ V}$ ; $I_D = 5\text{ A}$ ; $T_j = 25\text{ }^{\circ}\text{C}$
		-	200	-	$\text{m}\Omega$	$V_{GS} = 6\text{ V}$ ; $I_D = 5\text{ A}$ ; $T_j = 125\text{ }^{\circ}\text{C}$
Gate resistance	$R_G$	-	3.5	-	$\Omega$	$f = 5\text{ MHz}$ ; open drain

**Table 6 Dynamic Characteristics**

Parameters	Symbols	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Input capacitance	$C_{iss}$	-	125	-	pF	$V_{GS} = 0\text{ V}$ ; $V_{DS} = 400\text{ V}$ ; $f = 100\text{ kHz}$
Output capacitance	$C_{oss}$	-	40	-	pF	$V_{GS} = 0\text{ V}$ ; $V_{DS} = 400\text{ V}$ ; $f = 100\text{ kHz}$
Reverse transfer capacitance	$C_{rss}$	-	0.5	-	pF	$V_{GS} = 0\text{ V}$ ; $V_{DS} = 400\text{ V}$ ; $f = 100\text{ kHz}$
Effective output capacitance, energy related <sup>1</sup>	$C_{o(er)}$	-	53	-	pF	$V_{GS} = 0\text{ V}$ ; $V_{DS} = 0\text{ to }400\text{ V}$
Effective output capacitance, time related <sup>2</sup>	$C_{o(tr)}$	-	81	-	pF	$V_{GS} = 0\text{ V}$ ; $V_{DS} = 0\text{ to }400\text{ V}$
Output charge	$Q_{oss}$	-	33	-	nC	$V_{GS} = 0\text{ V}$ ; $V_{DS} = 0\text{ to }400\text{ V}$

1.  $C_{o(er)}$  is the fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400 V.

2.  $C_{o(tr)}$  is the fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400 V.



**Table 7 Gate Charge Characteristics**

Parameters	Symbols	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Gate charge	$Q_G$	-	3.3	-	nC	$V_{GS} = 0 \text{ to } 6 \text{ V}; V_{DS} = 400 \text{ V};$ $I_D = 5 \text{ A}$
Gate-source charge	$Q_{GS}$	-	0.3	-	nC	
Gate-drain charge	$Q_{GD}$	-	1.25	-	nC	
Gate plateau voltage	$V_{Plat}$	-	2.4	-	V	$V_{DS} = 400 \text{ V}; I_D = 5 \text{ A}$

**Table 8 Reverse Conduction Characteristics**

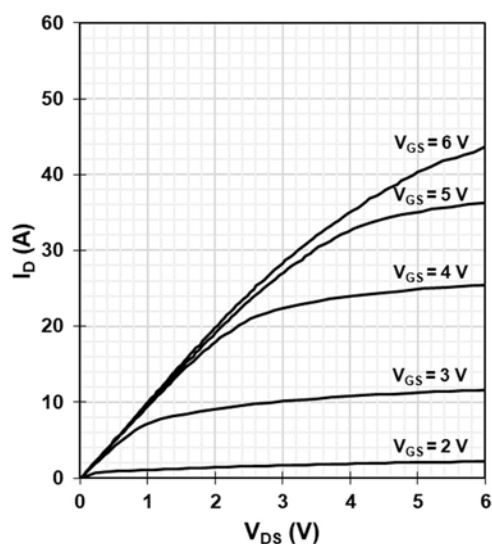
Parameters	Symbols	Values			Units	Notes/Test Conditions
		Min.	Typ.	Max.		
Source-drain reverse voltage	$V_{SD}$	-	2.5	-	V	$V_{GS} = 0 \text{ V}; I_{SD} = 5 \text{ A}$
Pulsed current, reverse	$I_{S, pulse}$	-	28	-	A	$V_{GS} = 6 \text{ V}$
Reverse recovery charge	$Q_{rr}$	-	0	-	nC	$I_{SD} = 5 \text{ A}; V_{DS} = 400 \text{ V}$
Reverse recovery time	$t_{rr}$	-	0	-	ns	
Peak reverse recovery current	$I_{rrm}$	-	0	-	A	



## Electrical Characteristics Diagrams

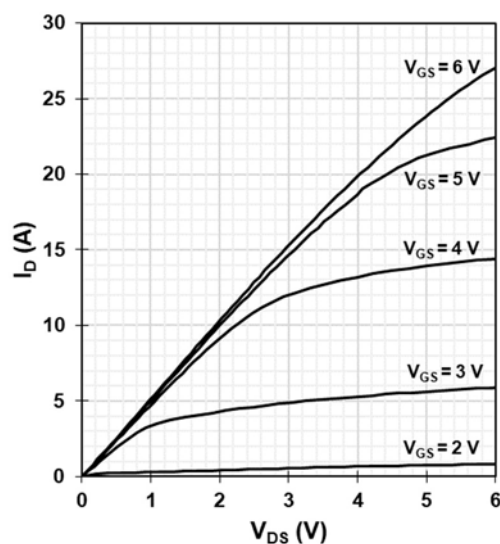
at  $T_j = 25^\circ\text{C}$ , unless specified otherwise.

Figure 1 Typ. output characteristics



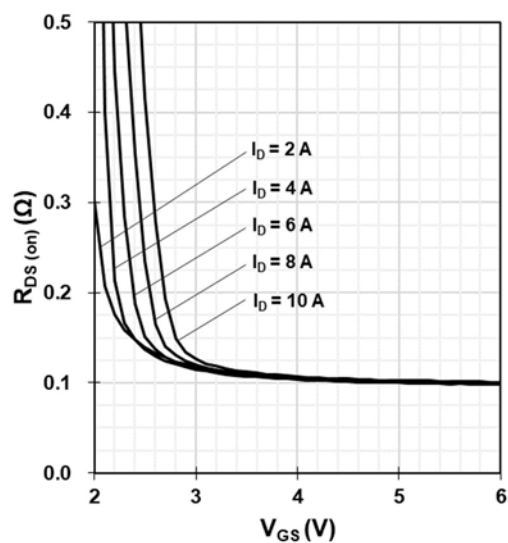
$$I_D = f(V_{DS}, V_{GS}); T_j = 25^\circ\text{C}$$

Figure 2 Typ. output characteristics



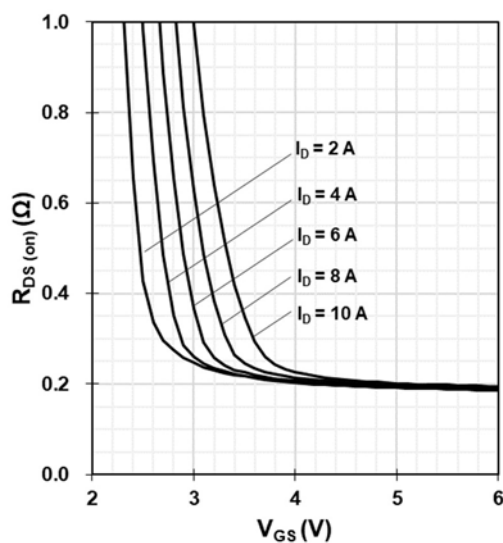
$$I_D = f(V_{DS}, V_{GS}); T_j = 125^\circ\text{C}$$

Figure 3 Typ. drain-source on-state resistance



$$R_{DS(on)} = f(I_D, V_{GS}); T_j = 25^\circ\text{C}$$

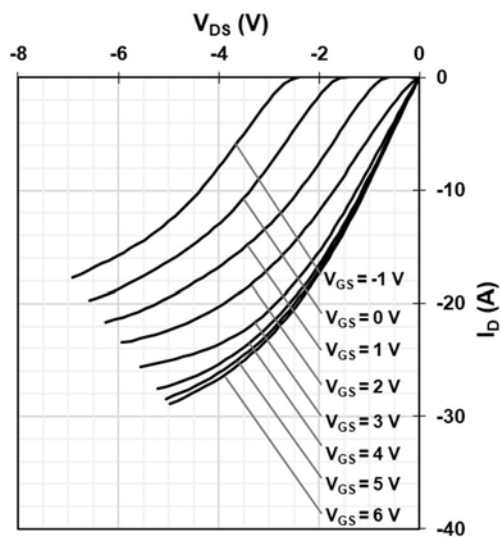
Figure 4 Typ. drain-source on-state resistance



$$R_{DS(on)} = f(I_D, V_{GS}); T_j = 125^\circ\text{C}$$

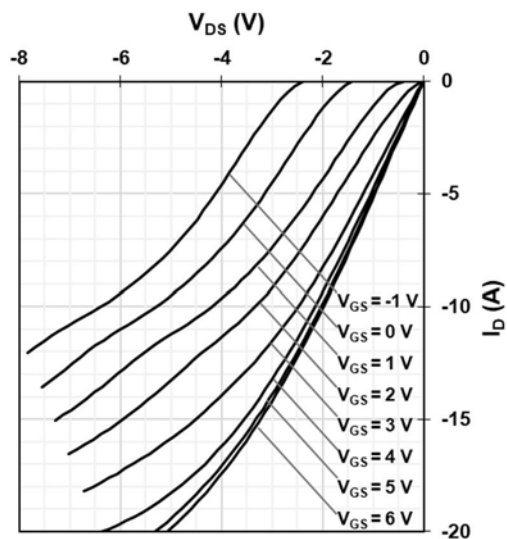


Figure 5 Typ. channel reverse characteristics



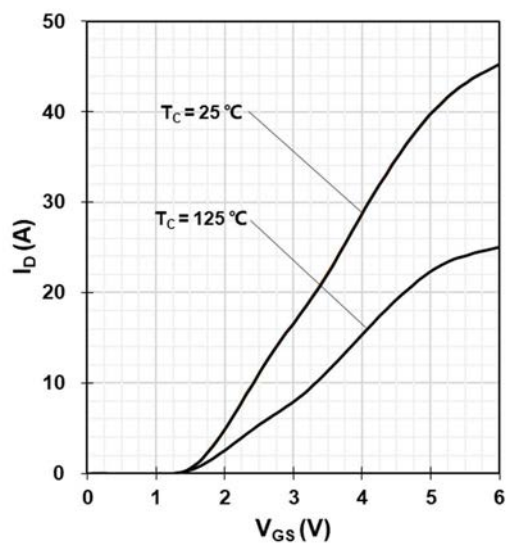
$$I_D = f(V_{DS}, V_{GS}); T_J = 25\text{ }^{\circ}\text{C}$$

Figure 6 Typ. channel reverse characteristics



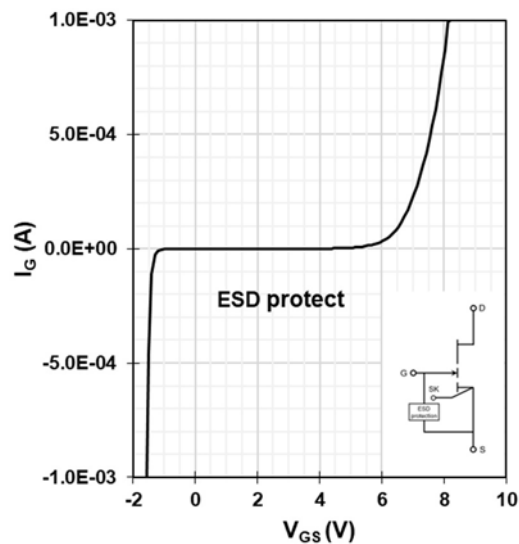
$$I_D = f(V_{DS}, V_{GS}); T_J = 125\text{ }^{\circ}\text{C}$$

Figure 7 Typ. transfer characteristics



$$I_D = f(V_{GS}); V_{DS} = 5\text{ V}$$

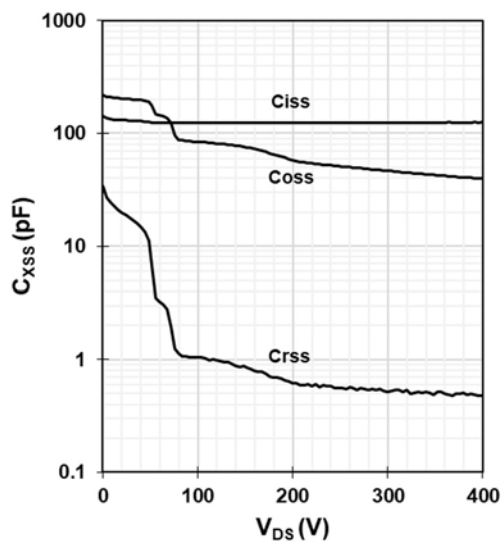
Figure 8 Typ. gate-to-source leakage



$$I_G = f(V_{GS}); I_G \text{ reverse turn on by ESD unit; } V_D = \text{open}$$

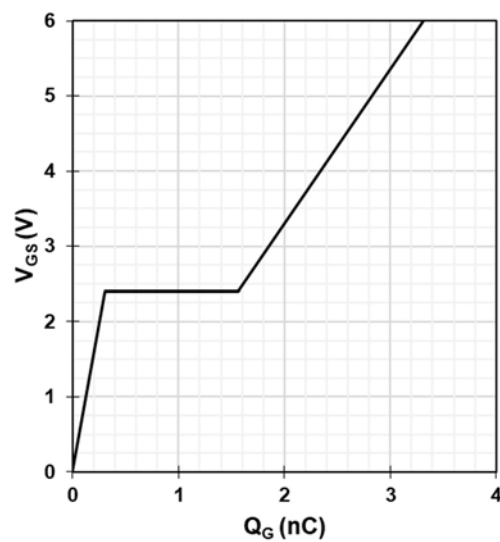


Figure 9 Typ. capacitances



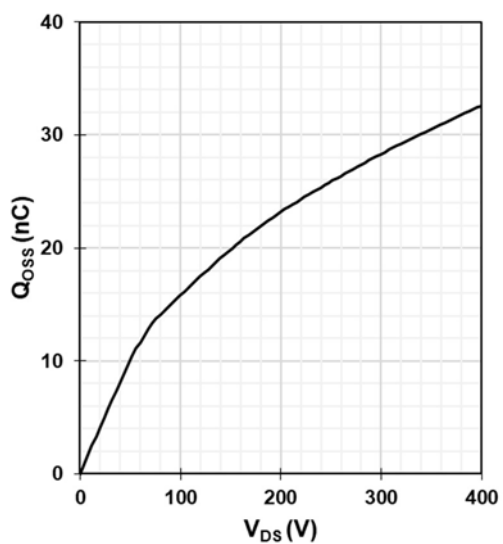
$C_{XSS} = f(V_{DS})$ ; Freq. = 100 kHz

Figure 10 Typ. gate charge



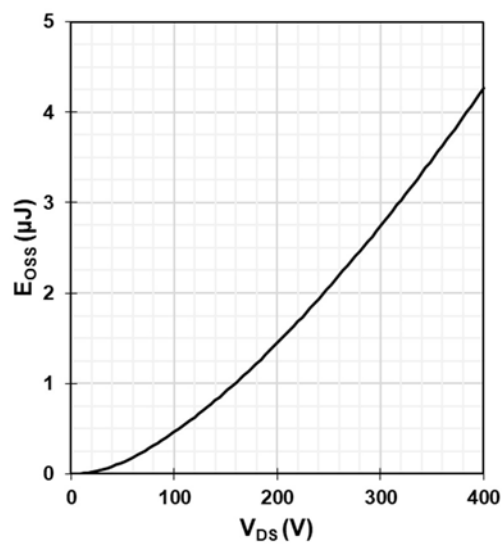
$V_{GS} = f(Q_G)$ ;  $V_{DC-LINK} = 400$  V;  $I_D = 5$  A

Figure 11 Typ. output charge



$Q_{OSS} = f(V_{DS})$ ; Freq. = 100 kHz

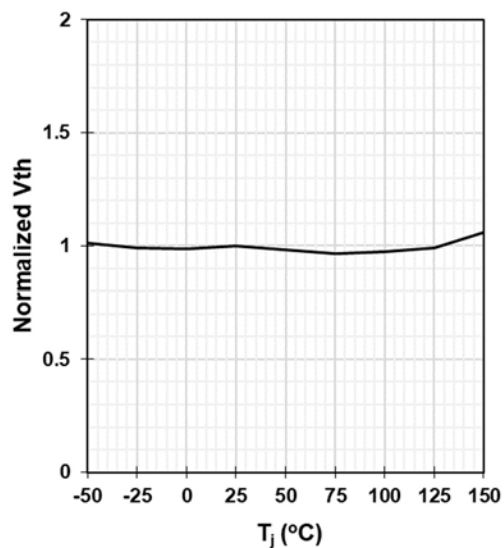
Figure 12 Typ. C<sub>oss</sub> stored energy



$E_{OSS} = f(V_{DS})$ ; Freq. = 100 kHz

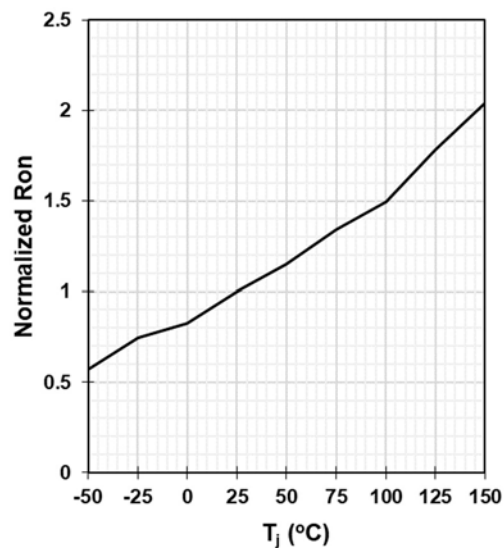


Figure 13 Gate threshold voltage



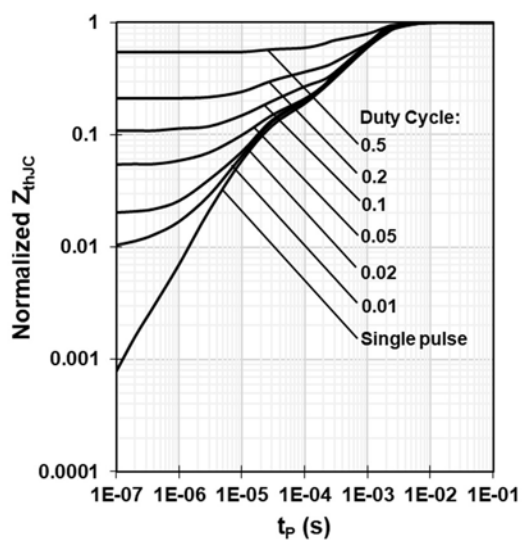
$$V_{TH} = f(T_j); V_{GS} = V_{DS}; I_D = 17.2 \text{ mA}$$

Figure 14 Drain-source on-state resistance



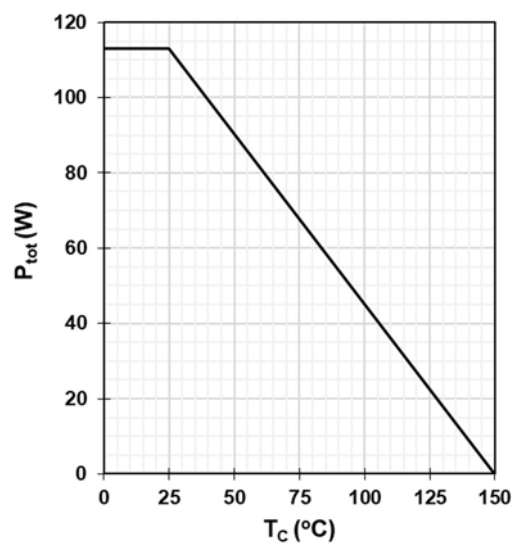
$$R_{DS(on)} = f(T_j); I_D = 5 \text{ A}; V_{GS} = 6 \text{ V}$$

Figure 15 Max. transient thermal impedance



$$Z_{thJC} = f(t_p, D)$$

Figure 16 Power dissipation

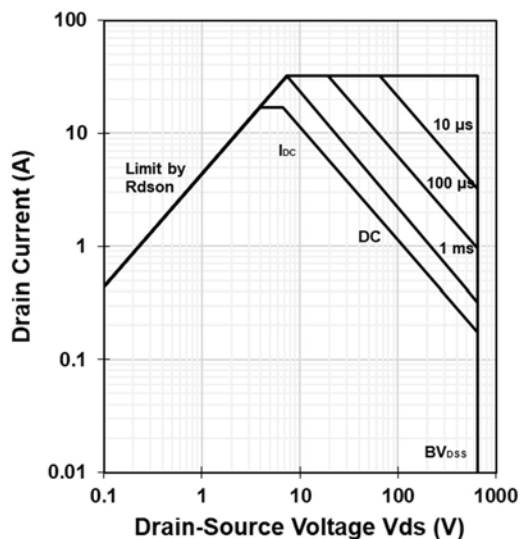


$$P_{tot} = f(T_c)$$



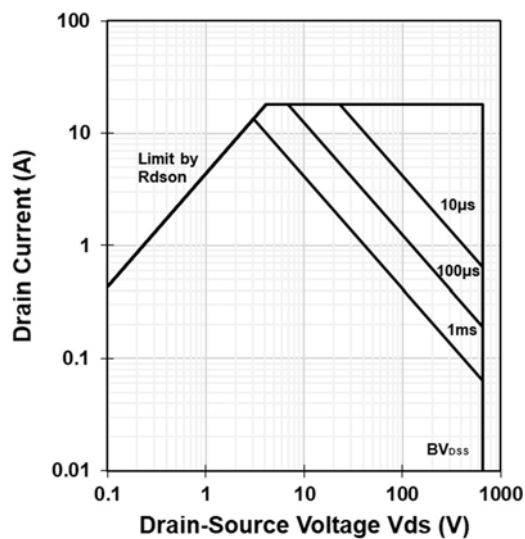


Figure 17 Safe operating area



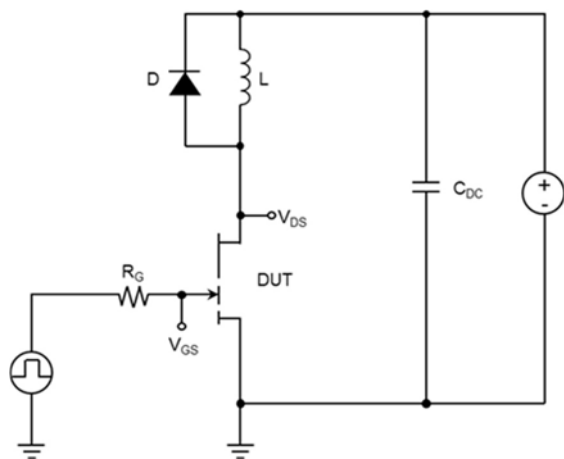
$$I_D = f(V_{DS}); T_C = 25\text{ }^{\circ}\text{C}$$

Figure 18 Safe operating area



$$I_D = f(V_{DS}); T_C = 125\text{ }^{\circ}\text{C}$$

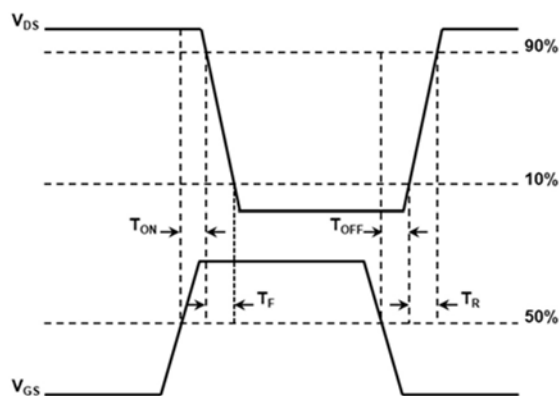
Figure 19 Max. transient thermal impedance



$$V_{DS} = 400\text{ V}, I_D = 10\text{ A}, L = 318\text{ }\mu\text{H}, V_{GS} = 6\text{ V},$$

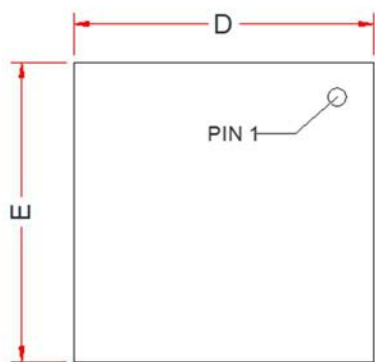
$$R_{on} = 10\text{ }\Omega, R_{off} = 2\text{ }\Omega$$

Figure 20 Typ. switching times waveform

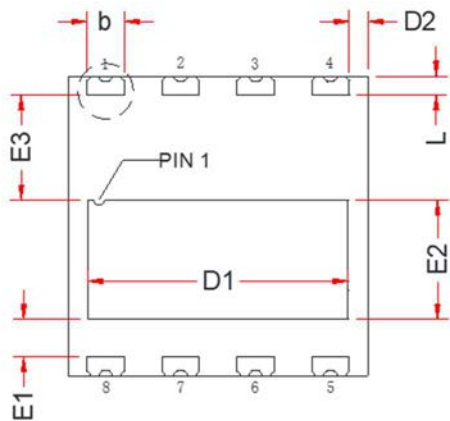




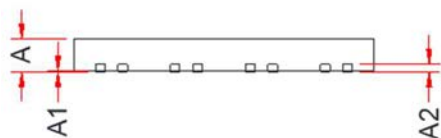
Package Outlines



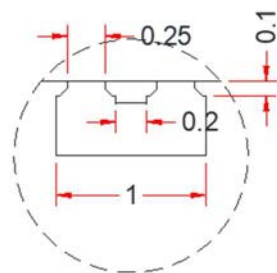
TOP VIEW



BOTTOM VIEW



SIDE VIEW



LEAD DETAIL

	MIN	MID	MAX
A	0.75	0.85	0.95
A1	0.00	0.02	0.05
A2	0.203REF		
b	0.95	1.00	1.05
D	8.00BSC		
D1	6.84	6.94	7.04
D2	0.40	0.50	0.60
E	8.00BSC		
E1	0.90	1.00	1.10
E2	3.10	3.20	3.30
E3	2.70	2.80	2.90
e	2.00BSC		
L	0.40	0.50	0.60



HXYY17N65JF  
GaN-on-Silicon Enhancement-mode

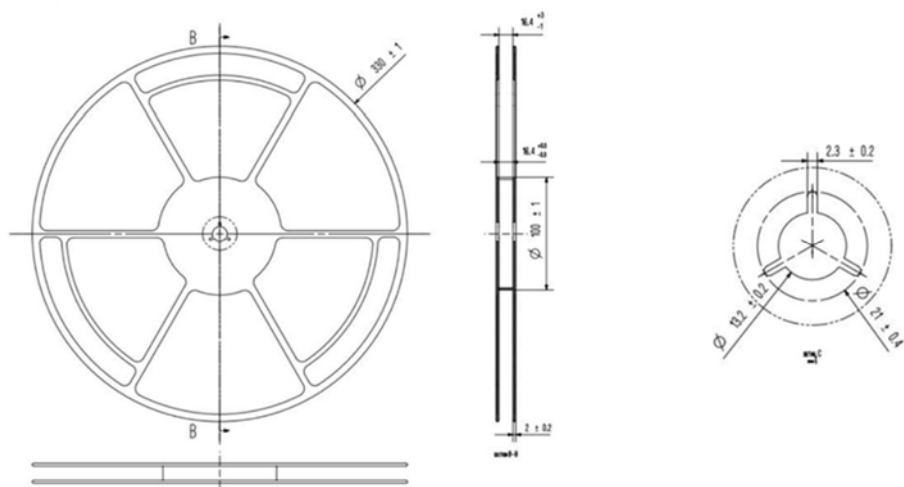
Technical drawing of a multi-hole metal plate. The drawing includes a top view, a side view (A-A), and a detail view of the hole pattern.

**Top View:** Shows a rectangular plate with a grid of holes. The overall width is labeled  $B$  and the overall height is labeled  $B_0$ . The plate has a thickness  $t$ . Section lines A-A and B-B are indicated.

**Side View (A-A):** Shows the profile of the plate. The width of the plate is labeled  $A_0$  and the height of the plate is labeled  $K_0$ .

**Detail View:** Shows a close-up of the hole pattern. The holes are arranged in a grid. The distance between the centers of adjacent holes is labeled  $P_1$  and  $P_2$ . The distance from the center of a hole to the edge of the plate is labeled  $P_0$ . The diameter of the hole is labeled  $\phi D_0$ . The distance between the centers of adjacent holes in the vertical direction is labeled  $\phi D_1$ . The distance from the center of a hole to the edge of the plate in the vertical direction is labeled  $B_0$ . The distance from the center of a hole to the edge of the plate in the horizontal direction is labeled  $A_0$ . The distance from the center of a hole to the edge of the plate in the vertical direction is labeled  $E$ . The distance from the center of a hole to the edge of the plate in the horizontal direction is labeled  $F$ . The width of the plate is labeled  $W$ .

SYMBOL	DIMENSION	SYMBOL	DIMENSION
W	16.00±0.30	10P0	40.00±0.20
E	1.75±0.10	P1	12.00±0.10
F	7.50±0.10	A0	8.30±0.10
D0	1.50±0.10	B0	8.30±0.10
D1	1.50±0.10	K0	1.10±0.10
P0	4.00±0.10	T	0.30±0.05
P2	2.00±0.10		





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